Search Notes			

Application/Control No.	Applicant(s)/Patent unde Reexamination		
10/528,754	TANAKA ET AL.		
Examiner	Art Unit		
Toi Duona	2074		

SEARCHED						
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34	49	74, 75	12/10/2006		TD	
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INTERFERENCE SEARCHED				
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SEARCH NOT (INCLUDING SEARCH)
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